

Peng Li

List of Publications by Year in descending order

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Version: 2024-02-01

10
papers

156
citations

1684188

5
h-index

1474206

9
g-index

10
all docs

10
docs citations

10
times ranked

190
citing authors

#	ARTICLE	IF	CITATIONS
1	Recent development of PeakForce Tapping mode atomic force microscopy and its applications on nanoscience. <i>Nanotechnology Reviews</i> , 2018, 7, 605-621.	5.8	78
2	Phase modulation mode of scanning ion conductance microscopy. <i>Applied Physics Letters</i> , 2014, 105, .	3.3	22
3	In-Phase Bias Modulation Mode of Scanning Ion Conductance Microscopy With Capacitance Compensation. <i>IEEE Transactions on Industrial Electronics</i> , 2015, 62, 6508-6518.	7.9	17
4	Development of Mechanostimulated Patch-Clamp System for Cellular Physiological Study. <i>IEEE/ASME Transactions on Mechatronics</i> , 2014, 19, 1138-1147.	5.8	15
5	Amplitude Modulation Mode of Scanning Ion Conductance Microscopy. <i>Journal of the Association for Laboratory Automation</i> , 2015, 20, 457-462.	2.8	11
6	Nanopatterning on calixarene thin films via low-energy field-emission scanning probe lithography. <i>Nanotechnology</i> , 2018, 29, 325301.	2.6	4
7	Advances in Scanning Ion Conductance Microscopy: Principles and Applications. <i>IEEE Nanotechnology Magazine</i> , 2021, 15, 17-25.	1.3	3
8	Development of a multi-functional multi-probe atomic force microscope system with optical beam deflection method. <i>Review of Scientific Instruments</i> , 2021, 92, 123705.	1.3	3
9	Lateral force calibration for atomic force microscope cantilevers using a suspended nanowire. <i>Nanotechnology</i> , 2020, 31, 475703.	2.6	2
10	High-speed Atomic Force Microscope Technology: A Review. <i>Current Nanoscience</i> , 2022, 18, 545-553.	1.2	1